

PolarHT[™] HiPerFET Power MOSFET

IXFH 69N30P IXFT 69N30P $V_{DSS} = 300 V \ I_{D25} = 69 A \ R_{DS(on)} \le 49 m\Omega \ t_{rr} \le 200 ns$

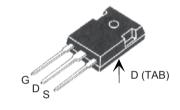
N-Channel Enhancement Mode Fast Intrinsic Diode Avalanche Rated



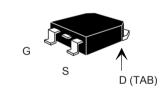
Symbol	Test Conditions	Maximum	Ratings
V _{DSS}	T ₁ = 25° C to 150° C	300	V
V _{DGR}	T_J° = 25° C to 150° C; R_{GS} = 1 M Ω	300	V
V _{GS}	Continuous	<u>+</u> 20	V
V _{GSM}	Transient	±30	V
I _{D25}	T _c =25°C	69	А
I _{DM}	$T_{\rm C}$ = 25° C, pulse width limited by $T_{\rm JM}$	200	Α
I _{AR}	T _C =25°C	69	Α
E _{AR}	T _C = 25° C	50	mJ
E _{AS}	T _c = 25° C	1.5	J
dv/dt	$I_{S} \le I_{DM}$, di/dt ≤ 100 A/ μ s, $V_{DD} \le V_{DSS}$,	10	V/ns
	$T_J \leq 150^{\circ} C$, $R_G = 4 \Omega$		
P _D	T _C =25°C	500	W
T		-55 +150	°C
T _{.IM}		150	°C
T _{stg}		-55 +150	°C
T,	1.6 mm (0.062 in.) from case for 10 s	300	°C
T _{SOLD}	Plastic body for 10 s	260	°C
M _d	Mounting torque	1.13/10	Nm/lb.in.
Weight	TO-247 TO-268	6 4	g g

Symbol (T _J = 25° C,	Test Conditions unless otherwise specified)		Characteristic Value Min. Typ. Max.			
BV _{DSS}	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$		300			V
$V_{_{\mathrm{GS(th)}}}$	$V_{DS} = V_{GS}$, $I_{D} = 4 \text{ mA}$		2.5		5.0	V
GSS	$V_{GS} = \pm 20 V_{DC}, V_{DS} = 0$				±100	nA
I _{DSS}	$V_{DS} = V_{DSS}$ $V_{GS} = 0 V$	T _J = 125° C			25 250	μ Α μ Α
R _{DS(on)}	V_{GS} = 10 V, I_{D} = 0.5 I_{D25} Pulse test, t ≤300 µs, duty	cycle d ≤ 2 %			49	mΩ

TO-247 (IXFH)



TO-268 (IXFT)



G = Gate D = Drain S = Source TAB = Drain

Features

- ¹ International standard packages
- Unclamped Inductive Switching (UIS) rated
- Low package inductance
 - easy to drive and to protect
- ¹ Fast intrinsic diode

Advantages

- ^I Easy to mount
- Space savings
- High power density



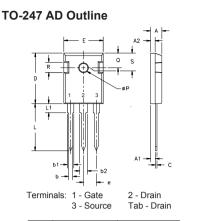
Symbo	ol	Test Conditions $(T_{_J} = 25^{\circ} \text{C},$			ristic Values ise specified) Max.
\mathbf{g}_{fs}		V_{DS} = 10 V; I_{D} = 0.5 I_{D25} , pulse test	30	48	S
\mathbf{C}_{iss})			4960	pF
\mathbf{C}_{oss}	}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$		760	pF
C _{rss}	J			190	pF
$\mathbf{t}_{d(on)}$)			25	ns
t _r		$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 V_{DSS}, I_{D} = I_{D25}$		25	ns
$\mathbf{t}_{d(off)}$		$R_{_{G}} = 4 \Omega $ (External)		75	ns
t _f)			27	ns
$\mathbf{Q}_{\mathrm{g(on)}}$)			156	180 nC
\mathbf{Q}_{gs}	}	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \text{ V}_{DSS}, I_{D} = 0.5 \text{ I}_{D25}$		32	nC
\mathbf{Q}_{gd}	J			79	nC
R _{thJC}					0.25° C/W
$\mathbf{R}_{\mathrm{thCS}}$		(TO-247)		0.21	° C/W

Source-Drain Diode

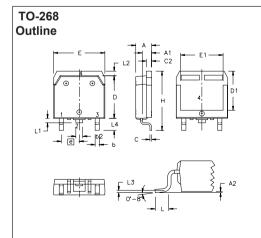
Characteristic Values

(T_J = 25° C, unless otherwise specified)

Symbo	I	Test Conditions	Min.	Тур.	Max.	
Is		V _{GS} = 0 V			69	Α
I _{SM}		Repetitive			200	Α
$\mathbf{V}_{\mathtt{SD}}$		$I_F = I_S$, $V_{GS} = 0$ V, Pulse test, t ≤300 μ s, duty cycle d≤ 2 %			1.5	V
t _{rr}	}	I _F = 25 A -di/dt = 100 A/μs		100	200	ns
\mathbf{Q}_{RM}	J	$V_{R} = 100 \text{ V}, V_{GS} = 0 \text{ V}$		500		nC



Dim.	Mill	imeter	Inc	hes
	Min.	Max.	Min.	Max.
Α	4.7	5.3	.185	.209
A ₁	2.2	2.54	.087	.102
A ₂	2.2	2.6	.059	.098
b	1.0	1.4	.040	.055
b ₁	1.65	2.13	.065	.084
b ₂	2.87	3.12	.113	.123
С	.4	.8	.016	.031
D	20.80	21.46	.819	.845
Е	15.75	16.26	.610	.640
е	5.20	5.72	0.205	0.225
L	19.81	20.32	.780	.800
L1		4.50		.177
ØP	3.55	3.65	.140	.144
Q	5.89	6.40	0.232	0.252
R	4.32	5.49	.170	.216
S	6.15	BSC	242	BSC



MY2	INCH	IES .	MILLIN	/ETERS
2 I M	MIN	MAX	MIN	MAX
Α	.193	.201	4.90	5.10
A1	.106	.114	2.70	2.90
A2	.001	.010	0.02	0.25
b	.045	.057	1.15	1.45
b2	.075	.083	1.90	2.10
С	.016	.026	0.40	0.65
C2	.057	.063	1.45	1.60
D	.543	.551	13.80	14.00
D1	.488	.500	12.40	12.70
E	.624	.632	15.85	16.05
E1	.524	.535	13.30	13.60
е	.215 BSC		5.45	BSC
Н	.736	.752	18.70	19.10
L	.094	.106	2.40	2.70
L1	.047	.055	1.20	1.40
L2	.039	.045	1.00	1.15
L3	.010 BSC		0.25	BSC
L4	.150	.161	3.80	4.10

Fig. 1. Output Characteristics @ 25 Deg. C

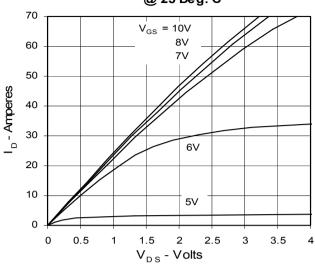


Fig. 3. Output Characteristics @ 125 Deg. C

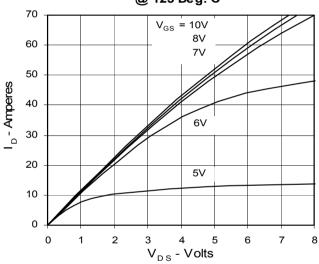


Fig. 5. $R_{DS(on)}$ Normalized to I_{D25} Value vs. I_{D}

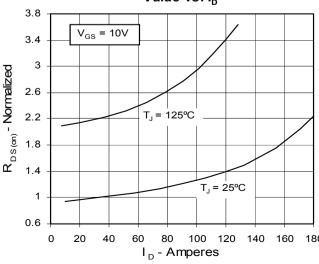


Fig. 2. Extended Output Characteristics

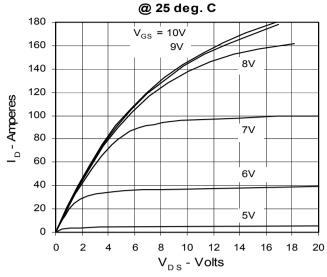


Fig. 4. $R_{DS(on)}$ Normalized to I_{D25} Value vs. Junction Temperature

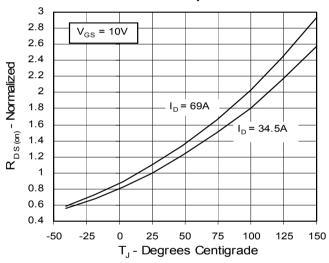


Fig. 6. Drain Current vs. Case Temperature

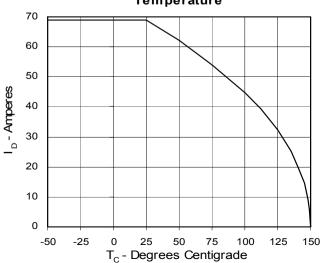




Fig. 7. Input Admittance

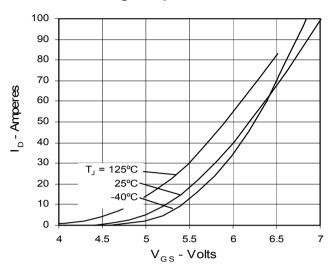


Fig. 9. Source Current vs. Source-To-Drain Voltage

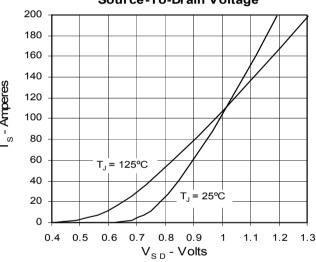


Fig. 11. Capacitance

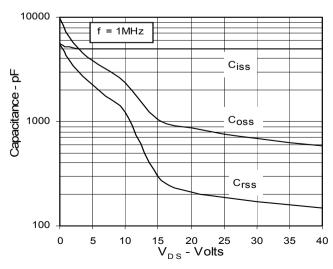


Fig. 8. Transconductance

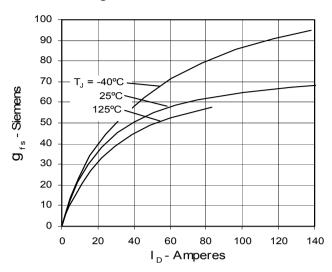


Fig. 10. Gate Charge

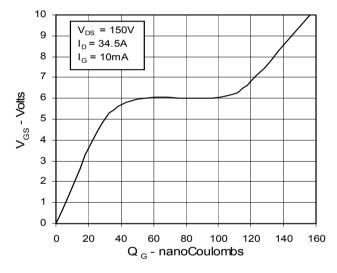
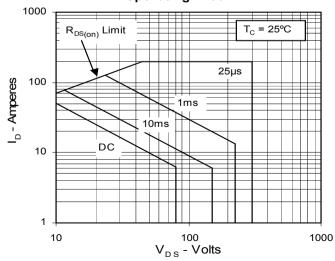


Fig. 12. Forward-Bias Safe Operating Area



IXYS reserves the right to change limits, test conditions, and dimensions.



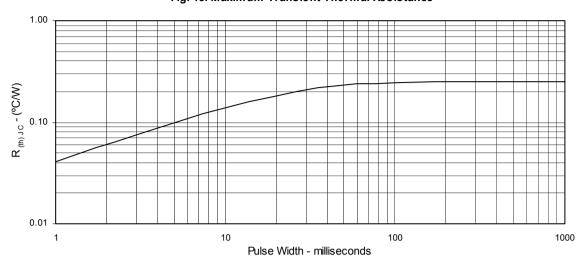


Fig. 13. Maximum Transient Thermal Resistance